## 74ABT16541 16-Bit Buffer/Line Driver with 3-STATE Outputs

#### **General Description**

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The ABT16541 contains sixteen non-inverting buffers with 3-STATE outputs designed to be employed as a memory and address driver, clock driver, or bus oriented transmitter/receiver. The device is byte controlled. Individual 3-STATE control inputs can be shorted together for 8-bit or 16-bit operation.

#### **Features**

- Separate control logic for each nibble
- 16-bit version of the ABT541
- Outputs sink capability of 64 mA, source capability of 32 mA
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed latchup protection
- High impedance glitch free bus loading during entire power up and power down cycle
- Non-destructive hot insertion capability

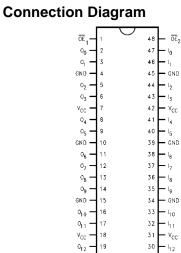
#### **Ordering Code:**

Order Number	Package Number	Package Description			
74ABT16541CSSC	MS48A	48-Lead Small Shrink Outline Package (SSOP), JEDEC MO-118, 0.300" Wide			
74ABT16541CMTD MTD48 48-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 6.1mm Wide					
Device also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.					

#### Logic Symbol 9 40 41 42 43 44 45 12 I\_4 I<sub>5</sub> 6 17 18 $|_3$ OF. ŌĒ -C -0 ŪE2 OF ٥, 02 03 0, 05 06 07 0, 012 013 014 01 0, ,

#### **Pin Descriptions**

Pin Names	Description
OE n	Output Enable Inputs (Active Low)
I <sub>0</sub> -I <sub>15</sub>	Inputs
O <sub>0</sub> –O <sub>15</sub>	Outputs



0<sub>13</sub> 20

GND 21

014 -22

ŌĒ 24

23 015

29

28 - GND 27

25 - 0E .

- 1<sub>13</sub>

 $\vdash_{h_4}$ 26

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#### **Truth Tables**

	Inputs		Outputs
OE 1	OE 2	I <sub>0</sub> –I <sub>7</sub>	0 <sub>0</sub> –0 <sub>7</sub>
L	L	L	L
L	L	н	н
н	Х	Х	Z
х	Н	х	Z
	Inputs		Outputs
OE 4	Inputs OE 3	I <sub>8</sub> -I <sub>15</sub>	Outputs O <sub>8</sub> -O <sub>15</sub>
OE 4	-	l <sub>8</sub> -l <sub>15</sub> L	-
	OE 3		0 <sub>8</sub> -0 <sub>15</sub>
L	OE 3	L	0 <sub>8</sub> -0 <sub>15</sub>

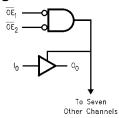
H = HIGH Voltage Level L = LOW Voltage Level

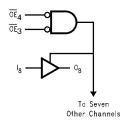
X = Immaterial Z = High Impedance

#### **Functional Description**

The ABT16541 contains sixteen non-inverting buffers with 3-STATE outputs. The device is byte (8 bits) controlled with each byte functioning identically, but independent of the other. The control pins can be shorted together to obtain full 16-bit operation.

#### Logic Diagrams





#### Absolute Maximum Ratings(Note 1)

	65°C to 150°C
Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	–55°C to +125°C
Junction Temperature under Bias	-55°C to +150°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Any Output	
in the Disabled or	
Power-Off State	-0.5V to 5.5V
in the HIGH State	-0.5V to V <sub>CC</sub>
Current Applied to Output	
in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
DC Latchup Source Current	–500 mA
Over Voltage Latchup (I/O)	10V

## Recommended Operating Conditions

Free Air Ambient Temperature	-40°C to +85°C
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate ( $\Delta V/\Delta t$ )	
Data Input	50 mV/ns
Enable Input	20 mV/ns

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Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

### **DC Electrical Characteristics**

Symbol	Para	meter	Min	Тур	Max	Units	Vcc	Conditions
VIH	Input HIGH Voltage		2.0			V		Recognized HIGH Signal
VIL	Input LOW Voltage				0.8	V		Recognized LOW Signal
V <sub>CD</sub>	Input Clamp Diode Volta	age			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH		2.5			V	Min	I <sub>OH</sub> = -3 mA
	Voltage		2.0			V	Min	I <sub>OH</sub> = -32 mA
V <sub>OL</sub>	Output LOW Voltage				0.55	V	Min	I <sub>OL</sub> = 64 mA
IIH	Input HIGH Current				1	μA	Max	V <sub>IN</sub> = 2.7V (Note 3)
					1	μΛ	IVIAA	$V_{IN} = V_{CC}$
I <sub>BVI</sub>	Input HIGH Current				7	μA	Max	V <sub>IN</sub> = 7.0V
	Breakdown Test							
IL	Input LOW Current				-1	μA	Max	V <sub>IN</sub> = 0.5V (Note 3)
					-1	μΛ	Wax	$V_{IN} = 0.0V$
V <sub>ID</sub>	Input Leakage Test		4.75			V	0.0	I <sub>ID</sub> = 1.9 μA
								All Other Pins Grounded
I <sub>OZH</sub>	Output Leakage Curren	t			10	μA	0–5.5V	$V_{OUT} = 2.7V; \overline{OE}_n = 2.0V$
I <sub>OZL</sub>	Output Leakage Curren	t			-10	μA	0–5.5V	$V_{OUT} = 0.5V; \overline{OE}_n = 2.0V$
I <sub>OS</sub>	Output Short-Circuit Cu	rrent	-100		-275	mA	Max	$V_{OUT} = 0.0V$
I <sub>CEX</sub>	Output HIGH Leakage (	Current			50	μA	Max	V <sub>OUT</sub> = V <sub>CC</sub>
I <sub>ZZ</sub>	Bus Drainage Test				100	μA	0.0	$V_{OUT} = 5.5V$
								All Other Pins GND
I <sub>CCH</sub>	Power Supply Current				100	μA	Max	All Outputs HIGH
I <sub>CCL</sub>	Power Supply Current				60	mA	Max	All Outputs LOW
I <sub>CCZ</sub>	Power Supply Current				100	μA	Max	$\overline{OE}_n = V_{CC}$
								All Others at $\mathrm{V}_{\mathrm{CC}}$ or GND
I <sub>CCT</sub>	Additional I <sub>CC</sub> /Input	Outputs Enabled			2.5	mA		$V_I = V_{CC} - 2.1V$
		Outputs 3-STATE			2.5	mA	Max	Enable Input $V_I = V_{CC} - 2.1$
		Outputs 3-STATE			50	μA		Data Input $V_I = V_{CC} - 2.1V$
								All Others at $\mathrm{V}_{\mathrm{CC}}$ or GND
I <sub>CCD</sub>	Dynamic I <sub>CC</sub>	No Load				mA/		Outputs Open, $\overline{OE}_n = GND$
	(Note 3)				0.1	MHz	Max	One Bit Toggling,
								50% Duty Cycle
V <sub>OLP</sub>	Quiet Output Maximum	Dynamic V <sub>OL</sub>		0.4	0.7	V	5.0	T <sub>A</sub> = 25°C (Note 4)
V <sub>OLV</sub>	Quiet Output Minimum I	Dynamic V <sub>OL</sub>	-1.3	-1.0		V	5.0	T <sub>A</sub> = 25°C (Note 4)
V <sub>OHV</sub>	Minimum HIGH Level D	ynamic Output Voltage	2.7	3.0		V	5.0	T <sub>A</sub> = 25°C (Note 6)
VIHD	Minimum HIGH Level D	ynamic Input Voltage	2.0	1.4		V	5.0	T <sub>A</sub> = 25°C (Note 5)

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#### DC Electrical Characteristics (Continued)

Symbol	Parameter	Min	Тур	Max	Units	V <sub>cc</sub>	Conditions	
V <sub>ILD</sub>	Maximum LOW Level Dynamic Input Voltage		1.2	0.8	V	5.0	$T_A = 25^{\circ}C$ (Note 5)	
Note 3: G	Note 3: Guaranteed but not tested.							

Note 4: Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. One output at LOW. Guaranteed, but not tested.

Note 5: Max number of data inputs (n) switching. n-1 inputs switching 0V to 3V. Input-under-test switching: 3V to threshold (V<sub>ILD</sub>), 0V to threshold (V<sub>IHD</sub>). Guaranteed, but not tested.

Note 6: Max number of outputs defined as (n). n - 1 data inputs are driven 0V to 3V. One output HIGH. Guaranteed, but not tested.

#### **AC Electrical Characteristics**

Symbol	Parameter	T <sub>A</sub> =+25°C V <sub>CC</sub> =+5V C <sub>L</sub> = 50 pF			T <sub>A</sub> = -40° V <sub>CC</sub> = 4 C <sub>L</sub> =	Units	
		Min	Тур	Max	Min	Max	
t <sub>PLH</sub>	Propagation	1.0	2.3	3.4	1.0	3.4	
t <sub>PHL</sub>	Delay Data to Outputs	1.0	2.7	3.9	1.0	3.9	ns
t <sub>PZH</sub>	Output Enable	1.5	3.5	5.2	1.5	5.2	ns
t <sub>PZL</sub>	Time	1.5	3.5	6.0	1.5	6.0	115
t <sub>PHZ</sub>	Output Disable	1.0	4.2	5.1	1.0	5.1	
t <sub>PLZ</sub>	Time	1.0	3.2	5.1	1.0	5.1	ns

#### **Extended AC Electrical Characteristics**

Symbol	Parameter	v	$-40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V - 5.5V$ $C_{L} = 50 \text{ pF}$ 16 Outputs Switching (Note 7)		V <sub>CC</sub> = 4 C <sub>L</sub> = 2 1 Output	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V-5.5V$ $C_{L} = 250 \text{ pF}$ 1 Output Switching (Note 8)		$T_{A} = -40 \degree C \text{ to } +85 \degree C$ $V_{CC} = 4.5V - 5.5V$ $C_{L} = 250 \text{ pF}$ 16 Outputs Switching (Note 9)	
		Min	Тур	Max	Min	Max	Min	Max	
<b>f</b> TOGGLE	Maximum Toggle Frequency		100						MHz
t <sub>PLH</sub>	Propagation Delay	1.5		5.0	1.5	6.0	2.5	8.0	
t <sub>PHL</sub>	Data to Outputs	1.5		5.3	1.5	6.0	2.5	8.0	ns
t <sub>PZH</sub>	Output Enable	1.5		6.5	2.5	7.8	2.5	9.5	
t <sub>PZL</sub>	Time	1.5		6.5	2.5	7.8	2.5	8.5	ns
t <sub>PHZ</sub>	Output Disable	1.0		6.7	(Not	e 10)	(Not	e 10)	ns
t <sub>PLZ</sub>	Time	1.0		6.7					

Note 7: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.).

Note 8: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.

Note 9: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

Note 10: The 3-STATE delay times are dominated by the RC network (500Ω, 250 pF) on the output and have been excluded from the datasheet.

Symbol	Parameter	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V-5.5V$ $C_{L} = 50 \text{ pF}$ 16 Outputs Switching (Note 11) Max	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$ $V_{CC} = 4.5V-5.5V$ $C_{L} = 250 \text{ pF}$ 16 Outputs Switching (Note 12) Max	Units
t <sub>OSHL</sub> (Note 13)	Pin to Pin Skew HL Transitions	1.0	1.5	ns
t <sub>OSLH</sub> (Note 13)	Pin to Pin Skew LH Transitions	1.0	1.5	ns
t <sub>PS</sub> (Note 14)	Duty Cycle LH–HL Skew	1.5	1.5	ns
t <sub>OST</sub> (Note 13)	Pin to Pin Skew LH/HL Transitions	1.7	2.0	ns
t <sub>PV</sub> (Note 15)	Device to Device Skew LH/HL Transitions	2.0	2.5	ns

Note 11: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase

(i.e., all LOW-to-HIGH, HIGH-to-LOW, etc.)

Note 12: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.

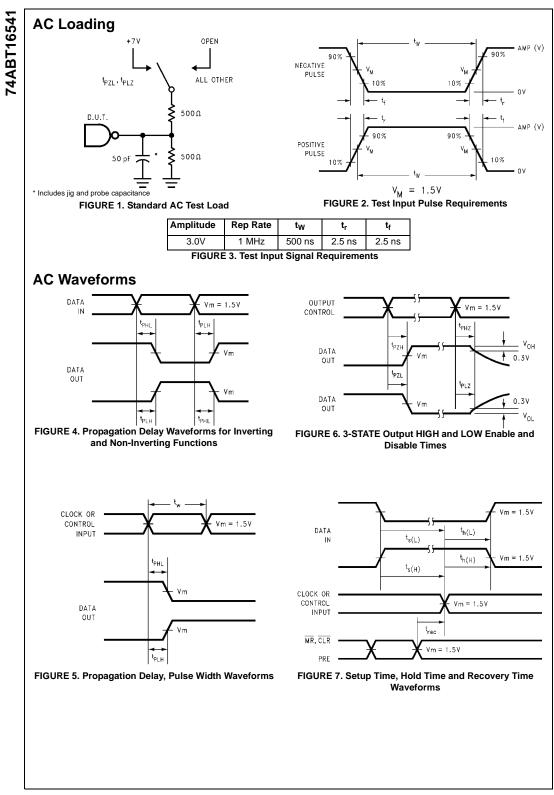
Note 13: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH-to-LOW ( $t_{OSHL}$ ), LOW-to-HIGH ( $t_{OSLH}$ ), or any combination switching LOW-to-HIGH and/or HIGH-to-LOW ( $t_{OST}$ ). The specification is guaranteed but not tested.

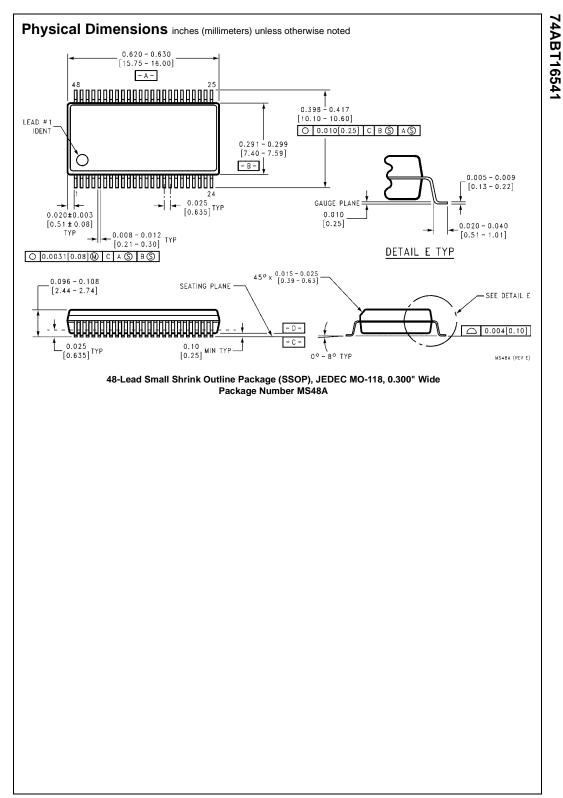
Note 14: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested. Note 15: Propagation delay variation for a given set of conditions (i.e., temperature and V<sub>CC</sub>) from device to device. This specification is guaranteed but not tested.

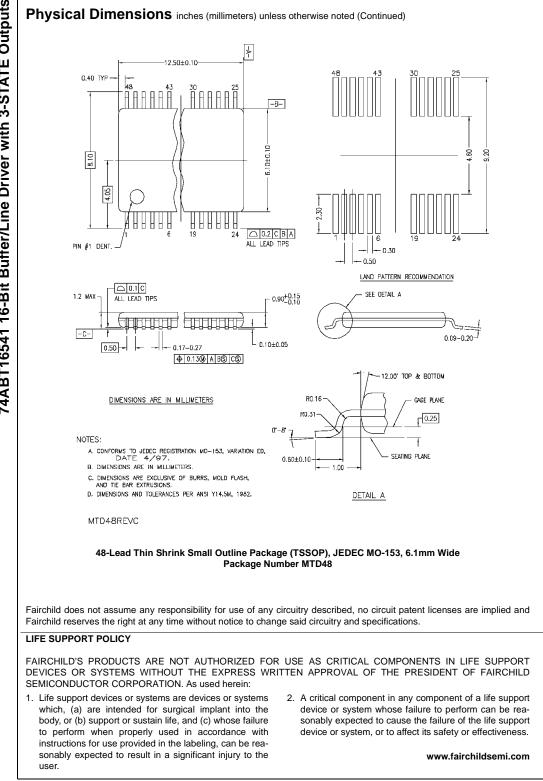
#### Capacitance

Symbol	Parameter	Тур	Units	Conditions T <sub>A</sub> = 25°C
C <sub>IN</sub>	Input Capacitance	5.0	pF	$V_{CC} = 5.0V$
C <sub>OUT</sub> (Note 16)	Output Capacitance	9.0	pF	$V_{CC} = 5.0V$

Note 16: C<sub>OUT</sub> is measured at frequency f = 1 MHz; per MIL STD-883, Method 3012.







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